Special Issue

Automated Testing of Modern Software Systems and Applications

Message from the Guest Editor

This Special Issue welcomes contributions regarding novel automated testing approaches improving the state-of-the-art on testing modern software with a particular (but not limited) focus on Web, Mobile, IoT, ML/AI-based systems, and applications. Topics of interest include but are not limited to the following:

- Testing of web applications;
- Testing of mobile applications (e.g., Android, iOS);
- Testing of Internet of Things systems;
- Testing of Machine Learning and Artificial Intelligence-based systems/applications
- Automated generation and maintenance of test cases for modern systems/applications;
- End-to-end testing of web and mobile applications;
- Acceptance and system testing of modern systems/applications;
- Machine Learning and Artificial Intelligence applied to software testing;
- Tools and frameworks for testing modern systems/applications;
- Empirical studies on modern systems/applications testing (e.g., experiments, surveys, literature reviews).

Guest Editor

Dr. Maurizio Leotta

Department of Computer Science, Bioengineering, Robotics and Systems Engineering (DIBRIS), University of Genova, 16146 Genoa, Italy

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closed (30 April 2024)

Software

About the Journal

Message from the Editor-in-Chief

Editor-in-Chief

Prof. Dr. Mirko Viroli
Department of Computer Science and Engineering, Alma Mater Studiorum Università di Bologna, via dell'Università 50, 47521 Cesena FC, Italy

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